


<b>Search Notes</b>  	<b>Application/Control No.</b>  10599050	<b>Applicant(s)/Patent Under Reexamination</b>  HOSOKAWA ET AL.
	<b>Examiner</b>  Marsha M Tsay	<b>Art Unit</b>  1656

SEARCHED			
Class	Subclass	Date	Examiner
435	214 (limited by text)	06.23.10	MT

SEARCH NOTES		
Search Notes	Date	Examiner
STIC SEQ ID NO: 2 search	05.27.10	MT
EAST (US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT) inventor and text search	06.23.10	MT
EAST (US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT) inventor and text updated	03.11.11	M.T.

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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